

Notice of References Cited	Application/Control No. 10/830,018	Applicant(s)/Patent Under Reexamination AKAMATSU, NAOKI	
	Examiner Leith A. Al-Nazer	Art Unit 2821	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0037020	03-2002	Shimura et al.	372/38.02
	B	US-5,406,172	04-1995	Bennett, Robert E.	315/112
	C	US-2003/0218794	11-2003	Takeda et al.	359/292
	D	US-6,553,044	04-2003	Eden, Richard C.	372/38.02
	E	US-5,438,579	08-1995	Eda et al.	372/34
	F	US-5,453,833	09-1995	Kawashima et al.	356/450
	G	US-5,936,987	08-1999	Ohishi et al.	372/29.014
	H	US-6,400,099	06-2002	Walker, Steven H.	315/291
	I	US-6,590,686	07-2003	Sekiya et al.	398/183
	J	US-2001/0026572	10-2001	Shimizu et al.	372/45
	K	US-2002/0150131	10-2002	Tsukiji et al.	372/34
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.